Features

- Low-voltage and Standard-voltage Operation
 - 2.7 (V_{CC} = 2.7V to 5.5V)
 - 1.8 (V_{CC} = 1.8V to 5.5V)
- User-selectable Internal Organization
 - 2K: 256 x 8 or 128 x 16
- 4K: 512 x 8 or 256 x 16
- 3-wire Serial Interface
- Sequential Read Operation
- 2 MHz Clock Rate (5V)
- Self-timed Write Cycle (10 ms Max)
- High Reliability
 - Endurance: 1 Million Write Cycles
 - Data Retention: 100 Years
- Automotive Grade, Extended Temperature and Lead-free/Halogen-free **Devices Available**
- 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead EIAJ SOIC, 8-lead MAP, 8-lead TSSOP and 8-ball dBGA2[™] Packages

Description

The AT93C56A/66A provides 2048/4096 bits of serial electrically erasable programmable read only memory (EEPROM) organized as 128/256 words of 16 bits each, when the ORG pin is connected to VCC and 256/512 words of 8 bits each when it is tied to ground. The device is optimized for use in many industrial and commercial applications where low power and low voltage operations are essential. The AT93C56A/66A is available in space-saving 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead EIAJ SOIC, 8-lead MAP, 8-lead TSSOP and 8-ball dBGA2[™] packages.

The AT93C56A/66A is enabled through the Chip Select pin (CS), and accessed via a 3-wire serial interface consisting of Data Input (DI), Data Output (DO), and Shift Clock (SK). Upon receiving a READ instruction at DI, the address is decoded and the data is

VCC

DC (7)

ORG

GND

8

6

5

Pin Configurations

Pin Name	Function
CS	Chip Select
SK	Serial Data Clock
DI	Serial Data Input
DO	Serial Data Output
GND	Ground
VCC	Power Supply
ORG	Internal Organization
DC	Don't Connect

8-le

4

CS

SK [

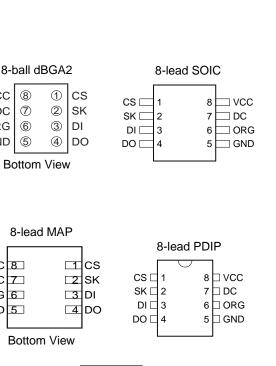
DI 3

DOD

ower S	upply	L	5011
ternal	Organization		
on't Co	onnect		8-l
			0-1
ad TSS	SOP	VCC	8
		DC	7
)		ORG	6
		GND	5

5

GND





3-wire Serial EEPROMs

2K (256 x 8 or 128 x 16)

4K (512 x 8 or 256 x 16)

AT93C56A AT93C66A

Advance Information

Rev. 3378E-SEEPR-1/04





clocked out serially on the data output pin DO. The WRITE cycle is completely selftimed and no separate ERASE cycle is required before WRITE. The WRITE cycle is only enabled when the part is in the ERASE/WRITE ENABLE state. When CS is brought "high" following the initiation of a WRITE cycle, the DO pin outputs the READY/BUSY status of the part.

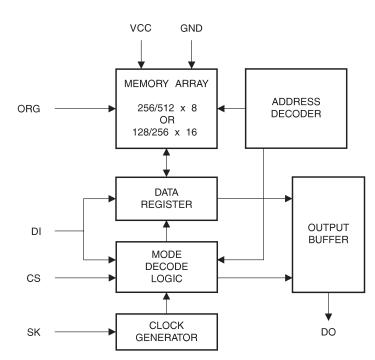
The AT93C56A/66A is available in 2.7V to 5.5V and 1.8V to 5.5V versions.

Absolute Maximum Ratings*

Operating Temperature55°C to +125°	, C
Storage Temperature	°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0)V
Maximum Operating Voltage6.2	5V
DC Output Current 5.0 n	۱A

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

Block Diagram



Note: When the ORG pin is connected to VCC, the x 16 organization is selected. When it is connected to ground, the x 8 organization is selected. If the ORG pin is left unconnected and the application does not load the input beyond the capability of the internal 1 Meg ohm pullup, then the x 16 organization is selected. The feature is not available on the 1.8V devices.

Pin Capacitance⁽¹⁾

Applicable over recommended operating range from $T_A = 25^{\circ}$ C, f = 1.0 MHz, $V_{CC} = +5.0$ V (unless otherwise noted).

Symbol	Test Conditions	Max	Units	Conditions
C _{OUT}	Output Capacitance (DO)	5	pF	$V_{OUT} = 0V$
C _{IN}	Input Capacitance (CS, SK, DI)	5	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

DC Characteristics

Applicable over recommended operating range from: $T_{AI} = -40^{\circ}$ C to $+85^{\circ}$ C, $V_{CC} = +1.8$ V to +5.5V, $T_{AE} = -40^{\circ}$ C to $+125^{\circ}$ C, $V_{CC} = +1.8$ V to +5.5V (unless otherwise noted).

Symbol	Parameter	Test Condition		Min	Тур	Max	Unit
V _{CC1}	Supply Voltage			1.8		5.5	V
V _{CC2}	Supply Voltage			2.7		5.5	V
V _{CC3}	Supply Voltage			4.5		5.5	V
	Querra la Querra est		READ at 1.0 MHz		0.5	2.0	mA
l _{CC}	Supply Current	$V_{CC} = 5.0V$	WRITE at 1.0 MHz		0.5	2.0	mA
I _{SB1}	Standby Current	V _{CC} = 1.8V	CS = 0V		0	0.1	μA
I _{SB2}	Standby Current	$V_{CC} = 2.7V$	CS = 0V		6.0	10.0	μA
I _{SB3}	Standby Current	$V_{CC} = 5.0V$	CS = 0V		17	30	μA
I _{IL}	Input Leakage	$V_{IN} = 0V$ to V_{CC}			0.1	3.0	μA
I _{OL}	Output Leakage	$V_{IN} = 0V$ to V_{CC}			0.1	3.0	μA
V _{IL1} ⁽¹⁾ V _{IH1} ⁽¹⁾	Input Low Voltage Input High Voltage	2.7V ≤V _{CC} ≤5.5V		-0.6 2.0		0.8 V _{CC} + 1	V
V _{IL2} ⁽¹⁾ V _{IH2} ⁽¹⁾	Input Low Voltage Input High Voltage	1.8V ≤V _{CC} ≤2.7V		-0.6 V _{CC} x 0.7		V _{CC} x 0.3 V _{CC} + 1	V
V _{OL1}	Output Low Voltage		I _{OL} = 2.1 mA			0.4	V
V _{OH1}	Output High Voltage	2.7V ⊴V _{CC} ⊴5.5V	I _{OH} = -0.4 mA	2.4			V
V _{OL2}	Output Low Voltage		I _{OL} = 0.15 mA			0.2	V
V _{OH2}	Output High Voltage	1.8V ≤V _{CC} ≤2.7V	I _{OH} = -100 μA	V _{CC} - 0.2			V

Note: 1. V_{IL} min and V_{IH} max are reference only and are not tested.





AC Characteristics

Applicable over recommended operating range from $T_{AI} = -40^{\circ}C$ to $+ 85^{\circ}C$, $T_{AE} = -40^{\circ}C$ to $+125^{\circ}C$, $V_{CC} = As$ Specified, CL = 1 TTL Gate and 100 pF (unless otherwise noted).

Symbol	Parameter	Test Condition		Min	Тур	Max	Units
f _{SK}	SK Clock Frequency	4.5V ≤V _{CC} ≤5.5V 2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V		0 0 0		2 1 0.25	MHz
t _{SKH}	SK High Time	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V		250 1000			ns
t _{SKL}	SK Low Time	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V		250 1000			ns
t _{cs}	Minimum CS Low Time	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V		250 1000			ns
t _{CSS}	CS Setup Time	Relative to SK	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V	50 200			ns
t _{DIS}	DI Setup Time	Relative to SK	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V	100 400			ns
t _{CSH}	CS Hold Time	Relative to SK		0			ns
t _{DIH}	DI Hold Time	Relative to SK	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V	100 400			ns
t _{PD1}	Output Delay to '1'	AC Test	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V			250 1000	ns
t _{PD0}	Output Delay to '0'	AC Test	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V			250 1000	ns
t _{SV}	CS to Status Valid	AC Test	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V			250 1000	ns
t _{DF}	CS to DO in High Impedance	AC Test CS = V _{IL}	2.7V ≤V _{CC} ≤5.5V 1.8V ≤V _{CC} ≤5.5V			150 400	ns
						10	ms
t _{WP}	Write Cycle Time		4.5V ≤V _{CC} ≤5.5V		3		ms
Endurance ⁽¹⁾	5.0V, 25°C, Page Mo	5.0V, 25°C, Page Mode					Write Cycles

Note: 1. This parameter is characterized and is not 100% tested.

		Ор	Addr	ess	D	ata	
Instruction	SB	Code	x 8	x 16	x 8	x 16	Comments
READ	1	10	A ₈ - A ₀	A ₇ - A ₀			Reads data stored in memory, at specified address.
EWEN	1	00	11XXXXXXX	11XXXXXX			Write enable must precede all programming modes.
ERASE	1	11	A ₈ - A ₀	A ₇ - A ₀			Erase memory location $A_n - A_0$.
WRITE	1	01	A ₈ - A ₀	A ₇ - A ₀	D ₇ - D ₀	D ₁₅ - D ₀	Writes memory location $A_n - A_0$.
ERAL	1	00	10XXXXXXX	10XXXXXX			Erases all memory locations. Valid only at $V_{CC} = 4.5V$ to 5.5V.
WRAL	1	00	01XXXXXXX	01XXXXXX	D ₇ - D ₀	D ₁₅ - D ₀	Writes all memory locations. Valid only at $V_{CC} = 5.0V \pm 10\%$ and Disable Register cleared.
EWDS	1	00	00XXXXXXX	00XXXXXX			Disables all programming instructions.

Instruction Set for the AT93C56A and AT93C66A

Note: The X's in the address field represent don't care values and must be clocked.

Functional Description

The AT93C56A/66A is accessed via a simple and versatile 3-wire serial communication interface. Device operation is controlled by seven instructions issued by the host processor. **A valid instruction starts with a rising edge of CS** and consists of a Start Bit (logic "1") followed by the appropriate Op Code and the desired memory Address location.

READ (READ): The Read (READ) instruction contains the Address code for the memory location to be read. After the instruction and address are decoded, data from the selected memory location is available at the serial output pin DO. Output data changes are synchronized with the rising edges of serial clock SK. It should be noted that a dummy bit (logic "0") precedes the 8- or 16-bit data output string. The AT93C56A/66A supports sequential read operations. The device will automatically increment the internal address pointer and clock out the next memory location as long as Chip Select (CS) is held high. In this case, the dummy bit (logic "0") will not be clocked out between memory locations, thus allowing for a continuous stream of data to be read.

ERASE/WRITE (EWEN): To assure data integrity, the part automatically goes into the Erase/Write Disable (EWDS) state when power is first applied. An Erase/Write Enable (EWEN) instruction must be executed first before any programming instructions can be carried out. Please note that once in the Erase/Write Enable state, programming remains enabled until an Erase/Write Disable (EWDS) instruction is executed or V_{CC} power is removed from the part.

ERASE (ERASE): The Erase (ERASE) instruction programs all bits in the specified memory location to the logical "1" state. The self-timed erase cycle starts once the ERASE instruction and address are decoded. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). A logic "1" at pin DO indicates that the selected memory location has been erased, and the part is ready for another instruction.





WRITE (WRITE): The Write (WRITE) instruction contains the 8 or 16 bits of data to be written into the specified memory location. The self-timed programming cycle, t_{WP} , starts after the last bit of data is received at serial data input pin DI. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). A logic "0" at DO indicates that programming is still in progress. A logic "1" indicates that the memory location at the specified address has been written with the data pattern contained in the instruction and the part is ready for further instructions. A **READY/BUSY status cannot be obtained if the CS is brought high after the end of the self-timed programming cycle, t_{WP}.**

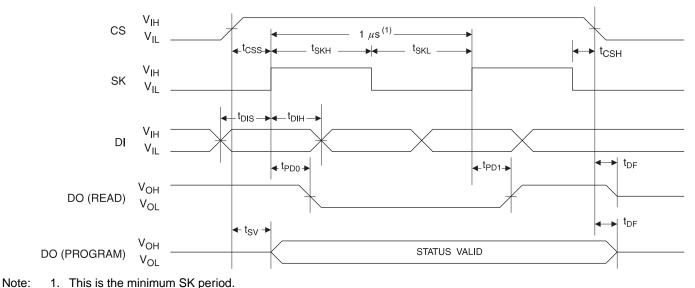
ERASE ALL (ERAL): The Erase All (ERAL) instruction programs every bit in the memory array to the logic "1" state and is primarily used for testing purposes. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). The ERAL instruction is valid only at $V_{CC} = 5.0V \pm 10\%$.

WRITE ALL (WRAL): The Write All (WRAL) instruction programs all memory locations with the data patterns specified in the instruction. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). The WRAL instruction is valid only at $V_{CC} = 5.0V \pm 10\%$.

ERASE/WRITE DISABLE (EWDS): To protect against accidental data disturb, the Erase/Write Disable (EWDS) instruction disables all programming modes and should be executed after all programming operations. The operation of the READ instruction is independent of both the EWEN and EWDS instructions and can be executed at any time.

Timing Diagrams



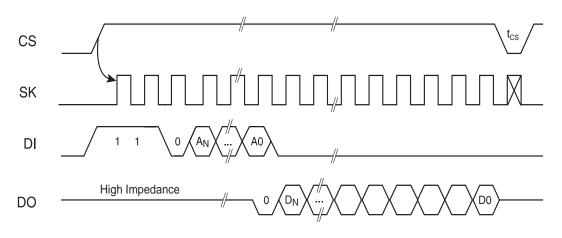


Organization Key for Timing Diagrams

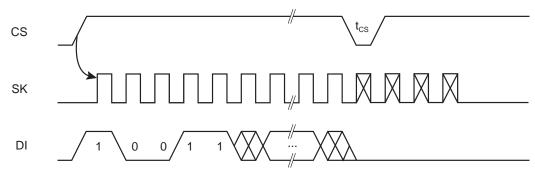
	AT93C56A (2K)		AT93C6	6A (4K)
I/O	x 8	x 16	x 8	x 16
A _N	A ₈ ⁽¹⁾	A ₇ ⁽²⁾	A ₈	A ₇
D _N	D ₇	D ₁₅	D ₇	D ₁₅

Notes: 1. A_8 is a DON'T CARE value, but the extra clock is required. 2. A_7 is a DON'T CARE value, but the extra clock is required.

READ Timing



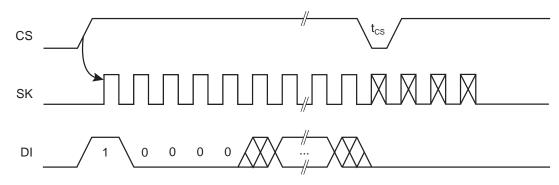
EWEN Timing



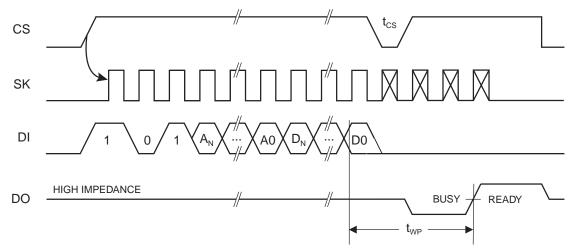




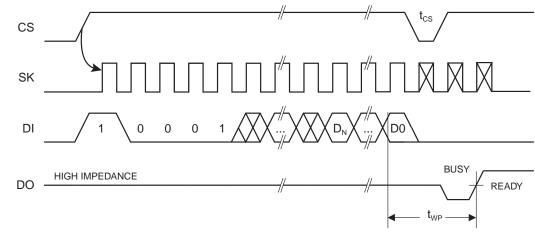
EWDS Timing



WRITE Timing



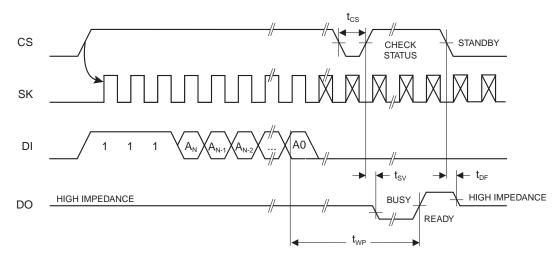
WRAL Timing⁽¹⁾



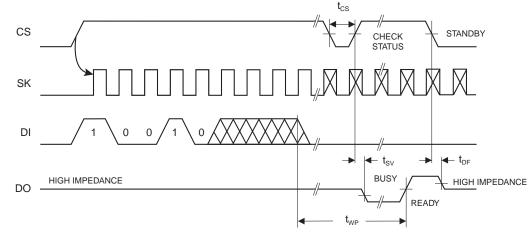
Note: 1. Valid only at V_{CC} = 4.5V to 5.5V.

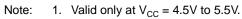
8 AT93C56A/66A

ERASE Timing



ERAL Timing⁽¹⁾









AT93C56A Ordering Information

Ordering Code	Package	Operation Range
AT93C56A-10PI-2.7	8P3	
AT93C56A-10SI-2.7	8S1	
AT93C56AW-10SI-2.7	8S2	Industrial Temperature
AT93C56A-10TI-2.7	8A2	(-40° C to 85° C)
AT93C56AU3-10UI-2.7	8U3-1	
AT93C56AY1-10YI-2.7	8Y1	
AT93C56A-10PI-1.8	8P3	
AT93C56A-10SI-1.8	8S1	
AT93C56AW-10SI-1.8	8S2	Industrial Temperature
AT93C56A-10TI-1.8	8A2	(-40° C to 85° C)
AT93C56AU3-10UI-1.8	8U3-1	
AT93C56AY1-10YI-1.8	8Y1	
AT93C56A-10SU-2.7	8S1	
AT93C56A-10SU-1.8	8S1	Lead-free/Halogen-free/ Industrial Temperature
AT93C56A-10TU-2.7	8A2	(-40° C to 85° C)
AT93C56A-10TU-1.8	8A2	(-40 0 10 85 0)
		Lead-free/Halogen-free/
AT93C56A-10SQ-2.7	8S1	High Grade/Extended Temperature
		(-40° C to 125° C)
AT02056A 108E 2.7	964	High Grade/Extended Temperature
AT93C56A-10SE-2.7	8S1	(-40° C to 125° C)

Note: For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

	Package Type
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)
8S2	8-lead, 0.200" Wide, Plastic Gull Wing Small Outline (EIAJ SOIC)
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)
8U3-1	8-ball, die Ball Grid Array Package (dBGA2)
8Y1	8-lead, 4.90 mm x 3.00 mm Body, Dual Footprint, Non-leaded, Miniature Array Package (MAP)
	Options
-2.7	Low-voltage (2.7V to 5.5V)
1.8	Low-voltage (1.8V to 5.5V)

AT93C66A Ordering Information

Ordering Code	Package	Operation Range
AT93C66A-10PI-2.7	8P3	
AT93C66A-10SI-2.7	8S1	
AT93C66AW-10SI-2.7	8S2	Industrial
AT93C66A-10TI-2.7	8A2	(-40° C to 85° C)
AT93C66AU3-10UI-2.7	8U3-1	
AT93C66AY1-10YI-2.7	8Y1	
AT93C66A-10PI-1.8	8P3	
AT93C66A-10SI-1.8	8S1	
AT93C66AW-10SI-1.8	8S2	Industrial
AT93C66A-10TI-1.8	8A2	(-40° C to 85° C)
AT93C66AU3-10UI-1.8	8U3-1	
AT93C66AY1-10YI-1.8	8Y1	
AT93C66A-10SU-2.7	8S1	
AT93C66A-10SU-1.8	8S1	Lead-free/Halogen-free/ Industrial Temperature
AT93C66A-10TU-2.7	8A2	
AT93C66A-10TU-1.8	8A2	(-40° C to 85° C)
		Lead-free/Halogen-free/
AT93C66A-10SQ-2.7	8S1	High Grade/Extended Temperature
		(-40° C to 125° C)
AT93C66A-10SE-2.7	8S1	High Grade/Extended Temperature
A10000A-100E-2.1	001	(-40° C to 125° C)

Note: For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

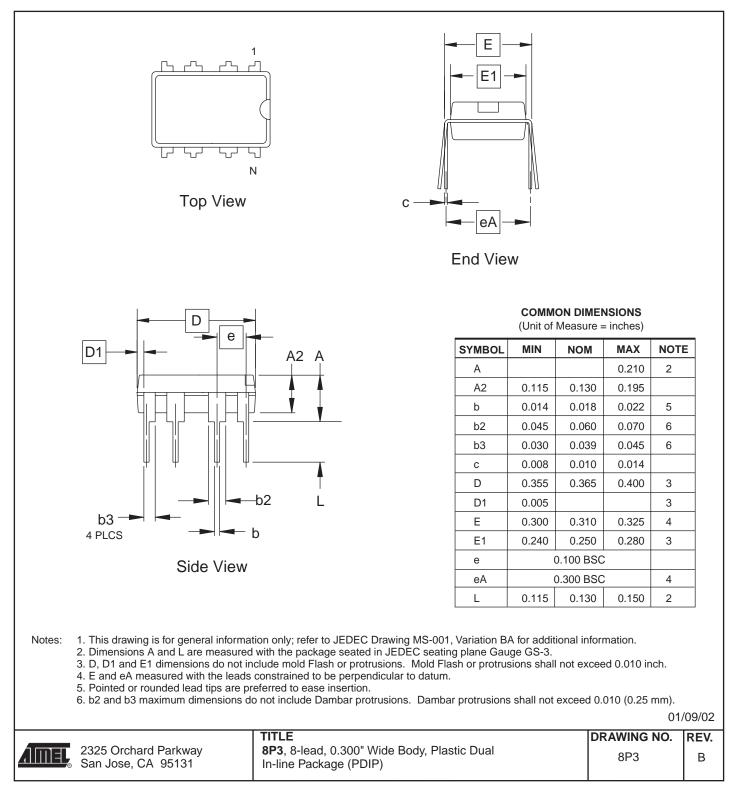
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8Y1	8-lead, 4.90 mm x 3.00 mm Body, Dual Footprint, Non-leaded, Miniature Array Package (MAP)		
	Options		
-2.7	Low-voltage (2.7V to 5.5V)		
-1.8	Low-voltage (1.8V to 5.5V)		



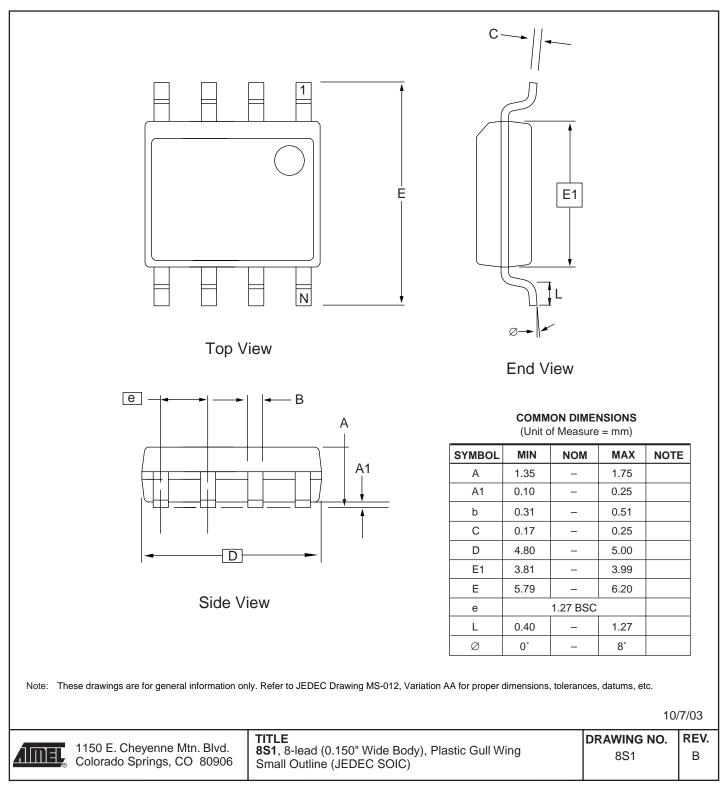


Packaging Information

8P3 – PDIP



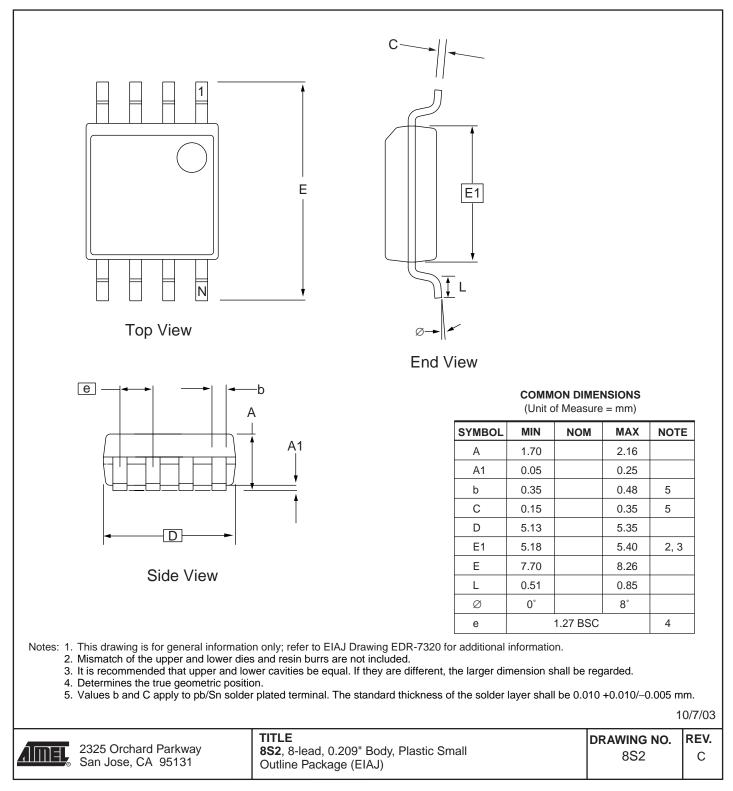
8S1 – JEDEC SOIC



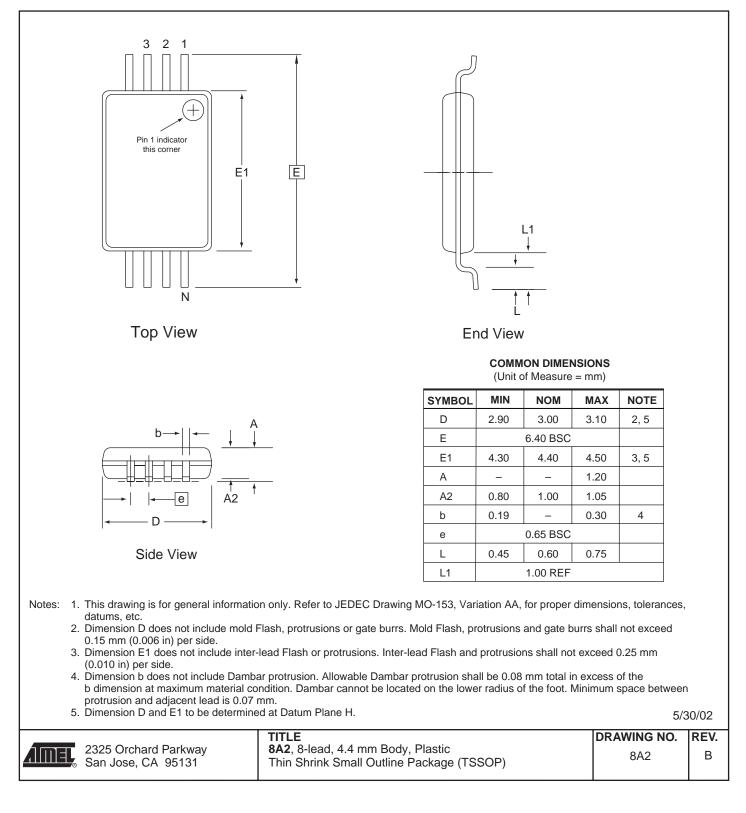




8S2 – EIAJ SOIC



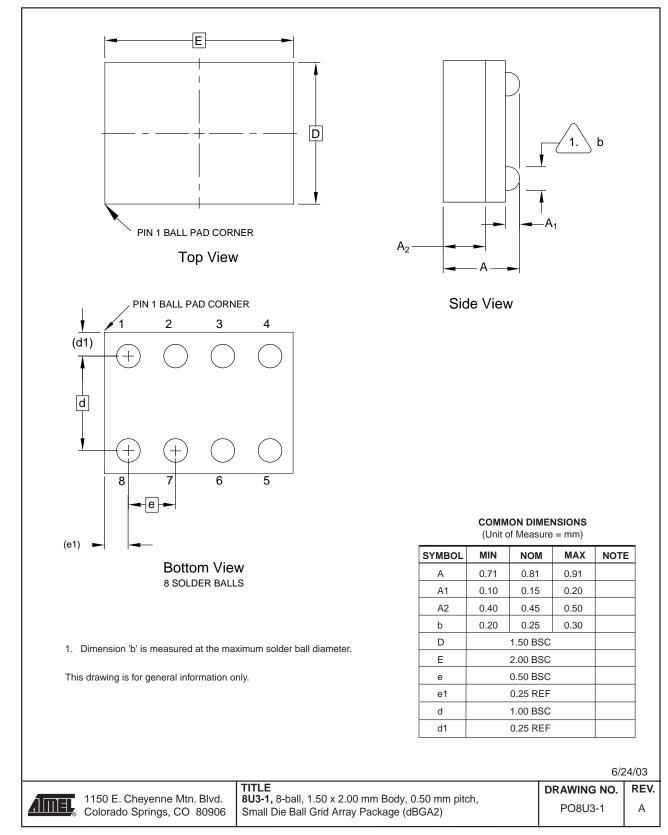
8A2 – TSSOP



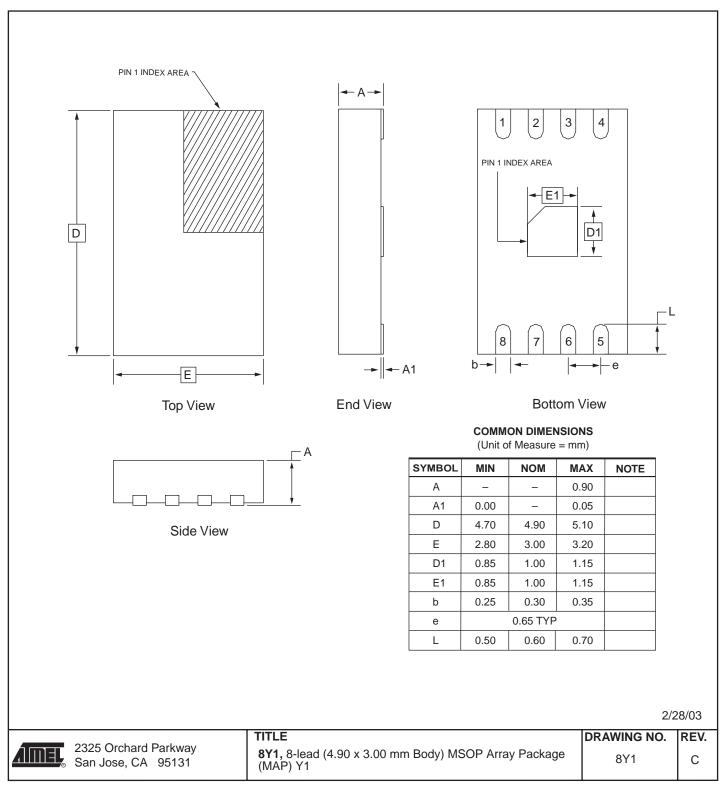




8U3-1 - dBGA2



8Y1 – MAP







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